PROCESSOR

30A

(SAMPLE MOUNT) /22

Inventor: Hui-Chuan Hung

Serial No.: 10/656,754 Filed: 09/06/2003

For: In-Situ Electron Beam Induced Current Detection
Attorney Doc. No.: 67,200-1152

.MARK+UP COPY

12 (FILAMENT)

14 (EXTRACTORS) [IMAGE | DISPLAY]

-18A | CONDENSERS)

21 (APERATUNE) | 20B | SIGNAL | 28

Figure 1

30B

24 (STAGE)

20 (MAGNET)

26 (DETECTOR)

26A

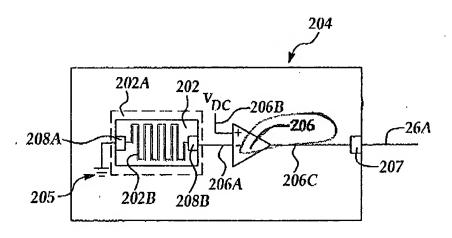


Figure 2A

-307

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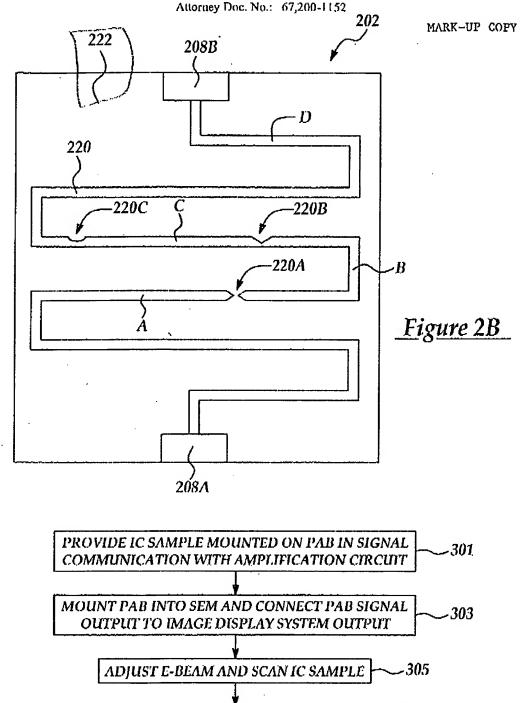


Figure 3

PASS EBIC TO AMPLIFICATION ELECTRONICS AND TO IMAGE DISPLAY SYSTEM TO PRODUCE CURRENT AND/OR

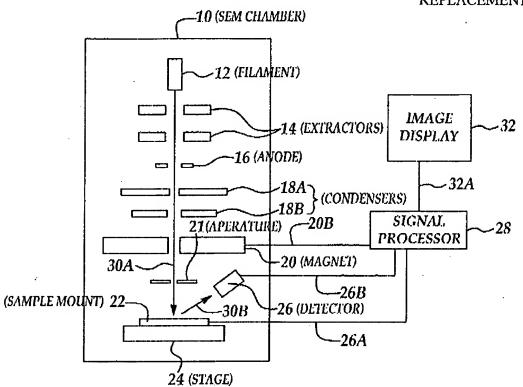
RESISTANCE CONTRAST IMAGE

Inventor: Hui-Chuan Hung

Scrial No.: 10/656,754 Filed: 09/06/2003
For: In-Situ Electron Beam Induced Current Detection

Attorney Doc. No.: 67,200-1152

REPLACEMENT SHEET



<u>Figure 1</u>

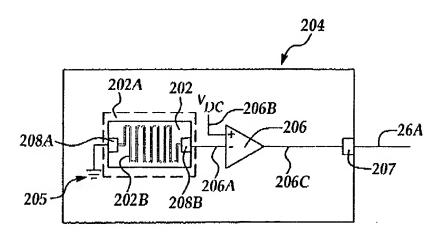


Figure 2A

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For: In-Situ Electron Beam Induced Current Detection

Attorney Dac. No.: 67,200-1152 202 REPLACEMENT SHEET 222 208B 220 220C 220B 220AFigure 2B 208A PROVIDE IC SAMPLE MOUNTED ON PAB IN SIGNAL 301 COMMUNICATION WITH AMPLIFICATION CIRCUIT MOUNT PAB INTO SEM AND CONNECT PAB SIGNAL -303

PROVIDE IC SAMPLE MOUNTED ON PAB IN SIGNAL
COMMUNICATION WITH AMPLIFICATION CIRCUIT

MOUNT PAB INTO SEM AND CONNECT PAB SIGNAL
OUTPUT TO IMAGE DISPLAY SYSTEM OUTPUT

ADJUST E-BEAM AND SCAN IC SAMPLE

303

PASS EBIC TO AMPLIFICATION ELECTRONICS AND TO IMAGE
DISPLAY SYSTEM TO PRODUCE CURRENT AND/OR
RESISTANCE CONTRAST IMAGE

307

Figure 3